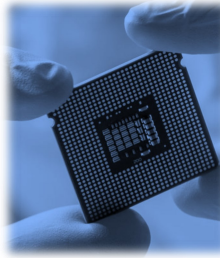




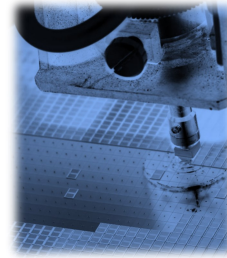
FAB



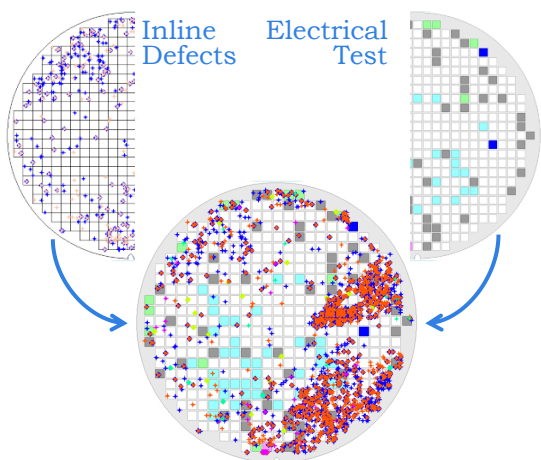
WAFER SORT



ASSEMBLY



TEST



Strip Maps
Tray Maps
Panel Maps



End-to-End Defect and Yield Data



- Semiconductor-specific visualizations
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Analytics and Root-Cause-Analysis Tools

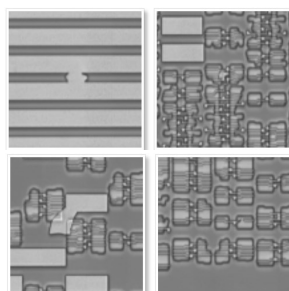
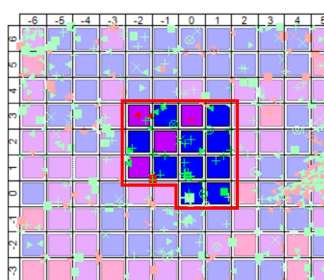
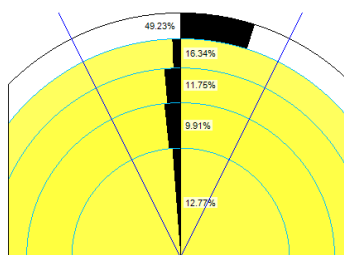


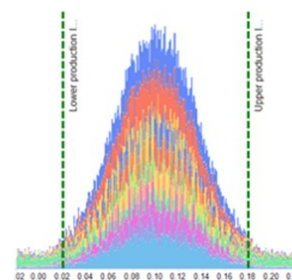
Image Gallery



Stacked Defect Maps



Zonal Maps



Charts and Plots

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- Process & Equipment Qualification and Monitoring
- Troubleshooting of low yields
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Value

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- Increase Fab Efficiency
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